

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>		ATTY DOCKET NO. YMOR:186	SERIAL NO. New Application			
		APPLICANT Takaki YOSHIDA et al.*				
		FILING DATE- October 27, 2000	GROUP			
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,825,191	10/20/98	Niijima et al.	324	751	
	5,663,967	9/2/97	Lindberg et al.	371	26	
	5,640,403	6/17/97	Ishiyama et al.	371	26	
	4,769,817	9/6/88	Krohn et al.	371	23	
	6,044,208	3/28/00	Papadopoulou et al.	395	500	
	5,581,475	12/3/96	Majors ..	364	491	
	5,325,309	6/28/94	Halaviati et al.	364	488	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION NO YES
OTHER DOCUMENT(S) <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>						
Defect-Based Test: A Key Enabler for Successful Migration to Structural Test, Intel Technology Journal Q1 '99, pp. 1-14.						
EXAMINER: <i>[Signature]</i>				DATE CONSIDERED: <i>5/19/2003</i>		

**EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.*